## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10629640	AMER, MAHER	
Examiner	Art Unit	
La Forgia, Christian	2131	

SEARCHED					
Class	Subclass	Date	Examiner		
380	28 AND parallel with scrambl\$3	11/30/06	clf		
380	210 AND parallel with scrambl\$3	11/30/06	clf		
380	268 AND parallel with scrambl\$3	11/30/06	clf		

SEARCH NOTES			
Search Notes	Date	Examiner	
East Search - seen enclosed printout	11/28/06	clf	
IEEE Search	11/28/06	clf	
ACM Search	11/28/06	clf	
Google Search	11/28/06	clf	
Inventor Search	11/28/06	clf	
Assignee Search	11/28/06	clf	
Cases Reviewed for Double Patenting: 10/629,644	11/28/06	clf	
EIC - for DW Choi document	11/28/06	clf	
East search - see enclosed printout	4/16/07	clf	
IEEE search	4/16/07	clf	
ACM search	4/16/07	clf	
Google Search	4/16/07	clf	
East search - see enclosed printout	8/11/07	clf	
IEEE search	8/11/07	clf	
ACM search	8/11/07	clf	
Google search	8/11/07	clf	

INTERFERENCE SEARCH					
Class	Subclass	Date	Examine		